Sheet 1 Form PTO-1449 U.S. Department of Commerce Attorney Docket No. 0756-1984 Serial No. Not Yet Assigned Patent and Trademark Office (Rev. 8-83) INFORMATION DISCLOSURE STATEMENT Applicant: Shunpei YAMAZAKI et al. (Use several sheets if necessary) Group: 2811 Filing Date: June 17, 1999 U.S. PATENT DOCUMENTS **Subclass** Examiner Patent Number Date Name Class Filing Date (if appr priate) Initial 12/03/96-5,581,092 -Takemura 5,500,538 03/19/96 Yamazaki et al. 5,147,826 09/15/92 Liu et al. 01/04/94 Fonash et al. 5,275,851 03/24/98 257 Yamazaki 350 5,731,613 192 65 12/03/96 Takemura 257 5.581.092 FOREIGN PATENT DOCUMENTS **Translation Document Number** Clas Subcl Date Country Yes No ass S OTHER DOCUMENTS (Including Author, Title, Relevant Pages, Date, Place of Publication) C. Hayzelden et al., "In Situ-Transmission Electron Microscopy Studies of Silicide-Mediated Crystallization of Amorphous Silicon" (3 pages) A.V. Dvurechenskii et al., "Transport Phenomena in Amorphous Silicon Doped by Ion Implantation of 3d Metals", Akademikian Lavrentev Prospekt 13, 630090 Novosibirsk 90, USSR, pp. 635-640. T. Hempel et al., "Needle-Like Crystallization of Ni Doped Amorphous Silicon Thin Films", Solid State Communications, Vol. 85, No. 11, pp. 921-924, 1993. R. Kakkad et al., "Crystallized Si films by low-temperature rapid thermal annealing of amorphous silicon," J.Appl. Phys., 65(5), March 1, 1989, pp. 2069-72. G. Liu et al., "Polycrystalline silicon thin film transistors on Corning 7059 glass substrates using short time, low-temperature processing, "Appl. Phys. Lett. 62(20), May 17, 1993, pp. 2554-2556. G. Liu et al., "Selective area crystallization of amorphous silicon films by low-temperatur rapid thermal annealing, "Appl. Phys. Lett. 55(7), August 14, 1989, pp. 660-662. R. Kakkad et al., "L w Temperature Selective Crystallization of Amorphous Silicon, "Journal of Non-Crystallin S lids, 115, 1989, pp. 66-68. Date Considered 12-14-99 hongrancy the Examiner

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